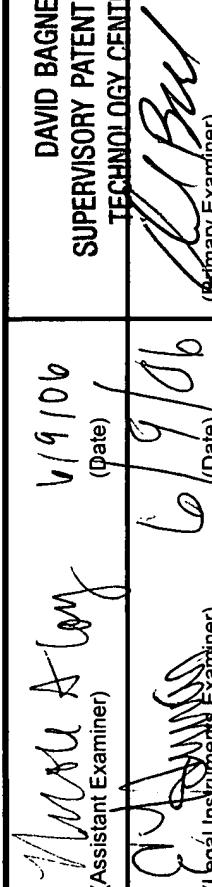
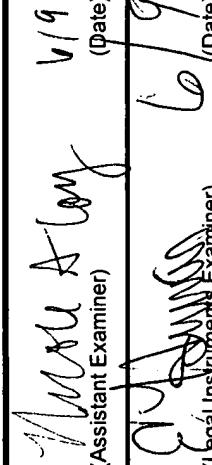
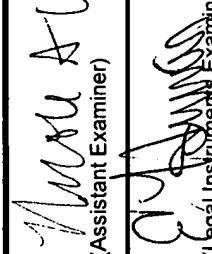
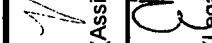


Issue Classification		Application/Control No.	Applicant(s)/Patent under Reexamination
		10807516	YOUAN, TOYOHIKO
Examiner		Art Unit	
Coy, Nicole		3672	
			

ORIGINAL		INTERNATIONAL CLASSIFICATION			
CLASS	SUBCLASS	CLAIMED			NON-CLAIMED
		E	2	1	
175	53				
CROSS REFERENCE(S)					
SUBCLASS (ONE SUBCLASS PER BLOCK)					
CLASS	175	406			
	405	184.1			
 DAVID BAGNELL SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3600 (Primary Examiner) 6/9/06 (Date)					
Total Claims Allowed:  WAN A. LEE (Assistant Examiner) 6/9/06 (Date)					
 O.G. Print Claim(s) 1 (Date)					
 O.G. Print Figure 1					